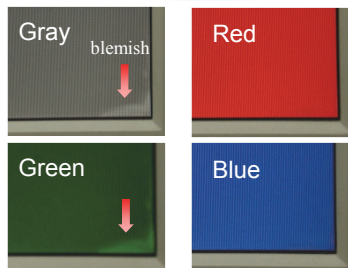


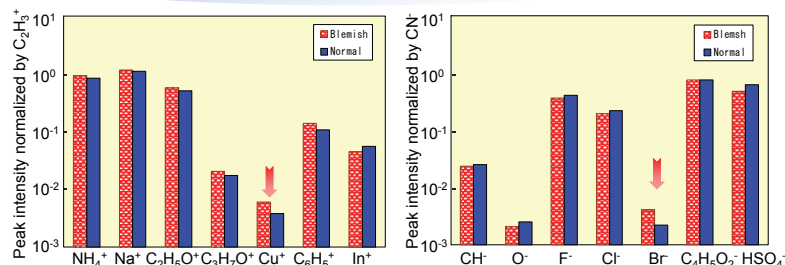
Analysis of Blemish in LCD Panels

TOF-SIMS (Time of Flight – Secondary Ion Mass Spectroscopy) and Resonant Raman spectroscopy has been successfully applied to analysis of blemish in Liquid Crystal Display panel.

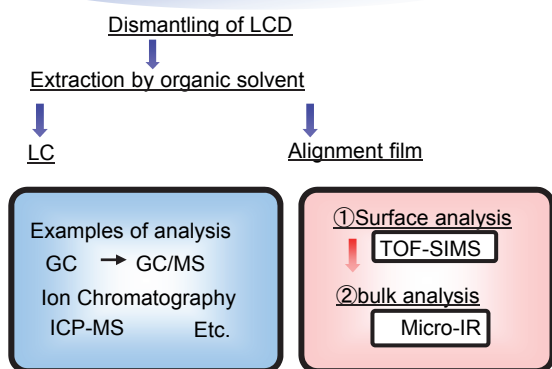
Images of blemish



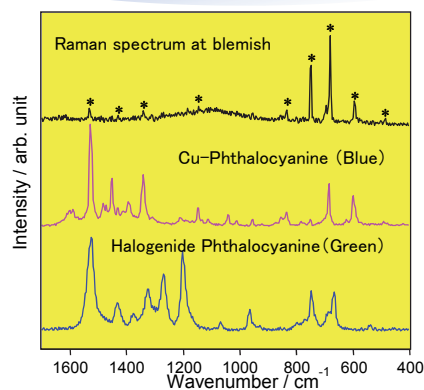
TOF-SIMS analysis on alignment film



Preparation procedure



Raman spectrum of LC



TOF-SIMS analysis shows higher concentration of Cu and Br at blemished area. ↓
Phthalocyanine related compounds are detected by resonant Raman spectrum.

Imaging depth profiles using TOF-SIMS

